



# Employing ECCs via Overprovisioning to Improve Flash Reliability: A New, Cost Efficient Approach

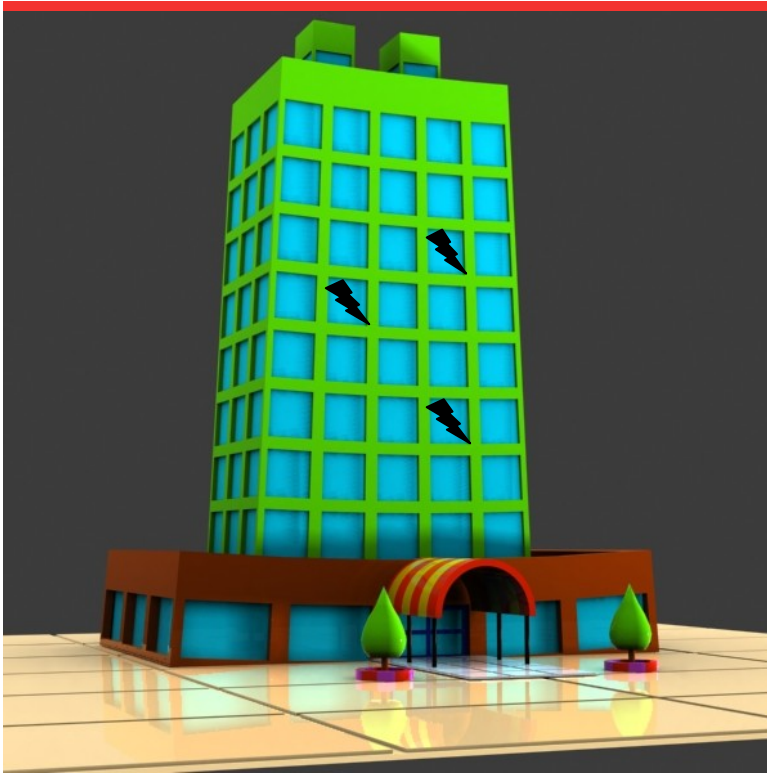
Stella Achtenberg, Eran Sharon, Idan Alrod  
Advanced Memory Solutions,

3-8-2016



Flash Memory Summit 2016 | Santa Clara, CA

# NAND Memory



## Mobile



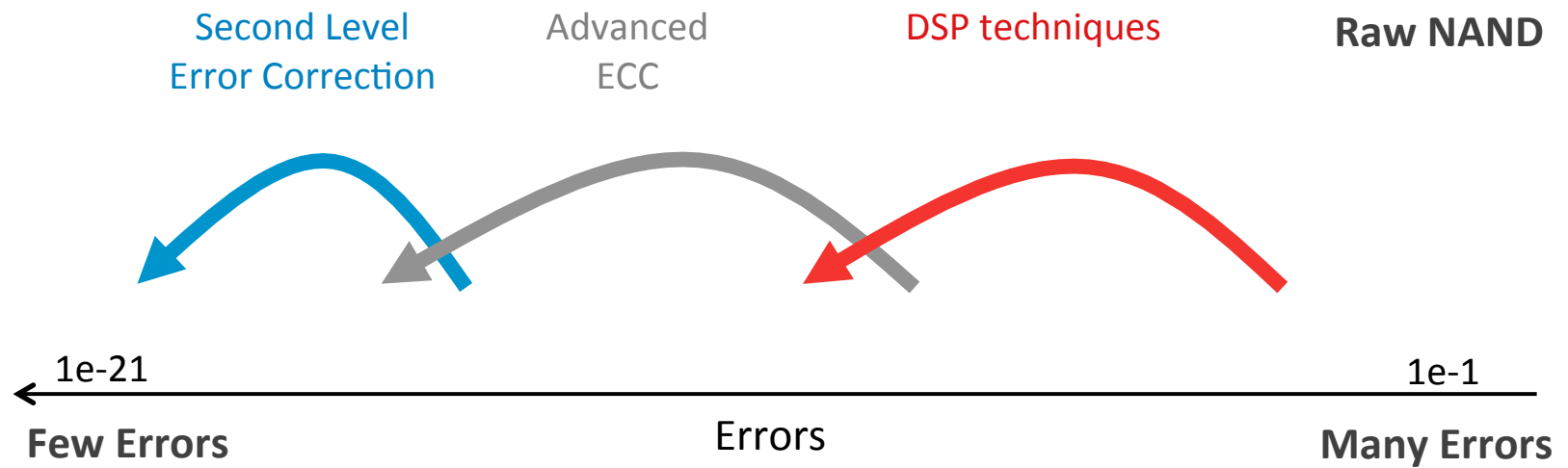
## Client SSD



## Enterprise SSD



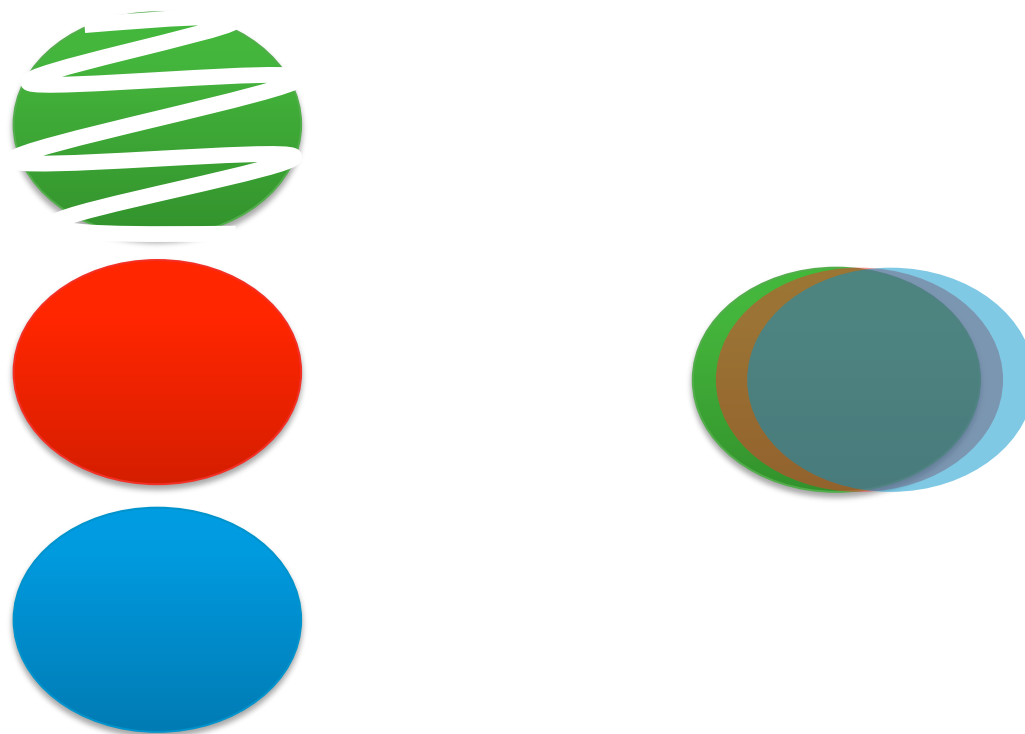
# Handling Random Errors



# NAND Memory

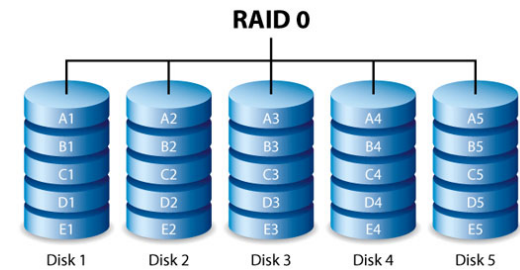
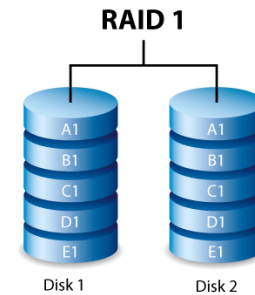
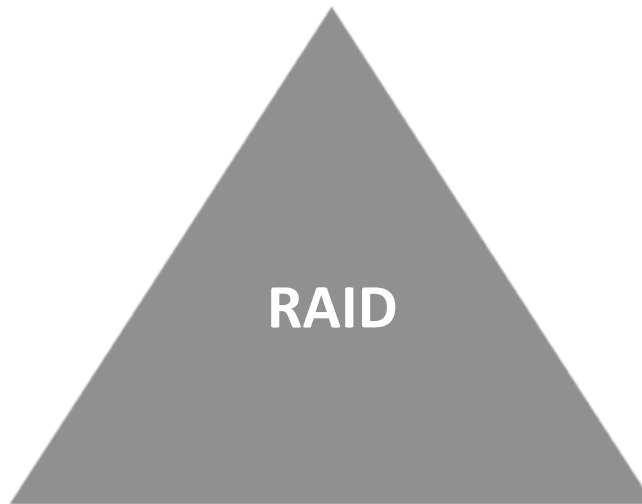
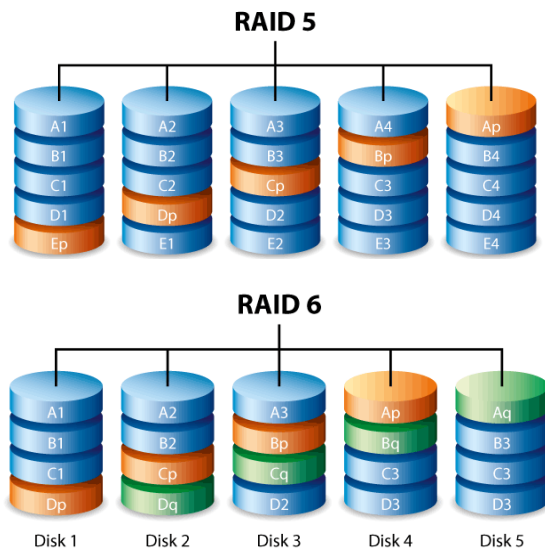


# RAID Example



# Handling Physical Defects

Overprovisioning



Reliability

Performance

# Storage Reliability Requirements

- A metric for occurrence of data errors per bits read:

*UBER = number of data errors / number of bits read*

- Extremely Low UBER requirements <  $10^{-18}$
- DPPM = Defective Parts per Million

Client SSD

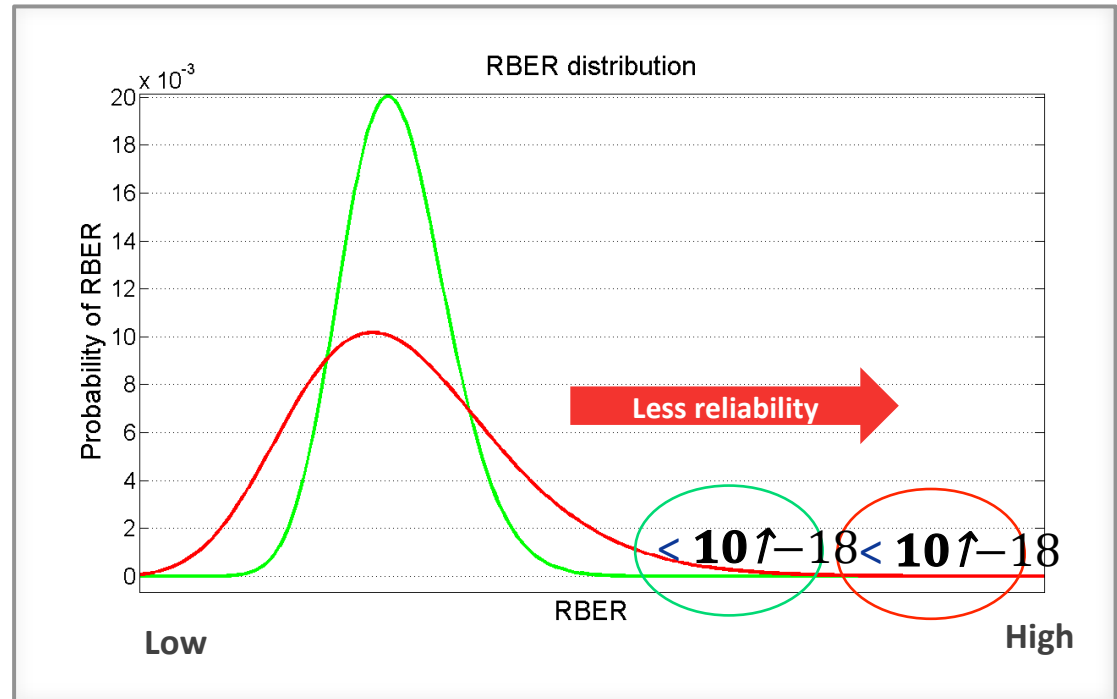


Enterprise SSD



# Problem statement

3-Dimensional stacking  
and process scaling  
increase RBER variability

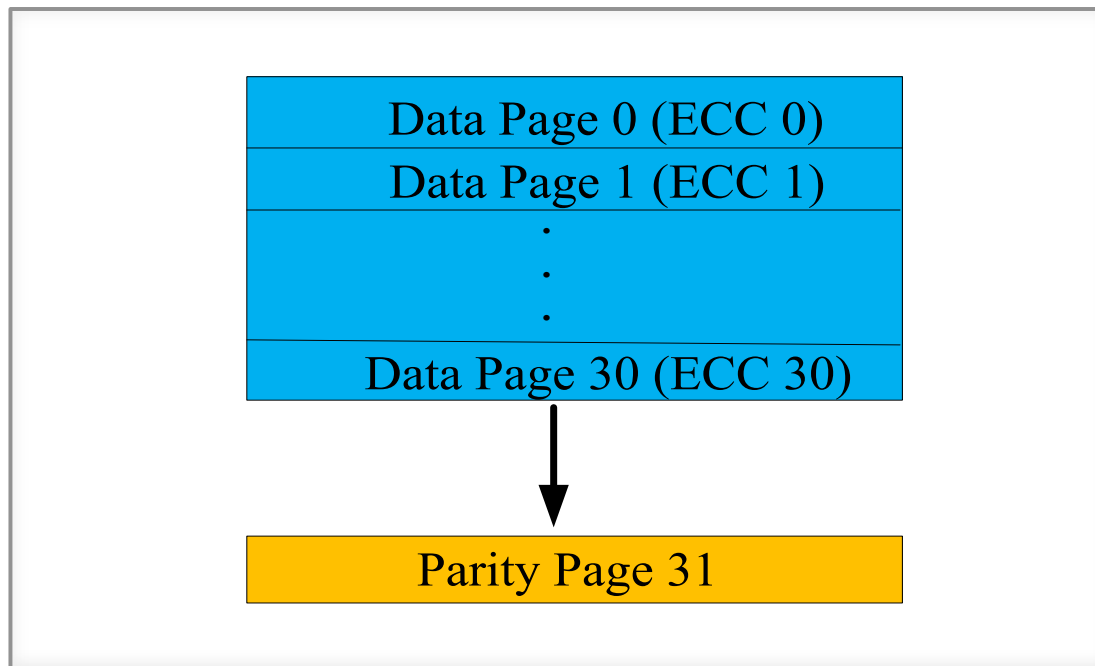




# Overprovisioning potential

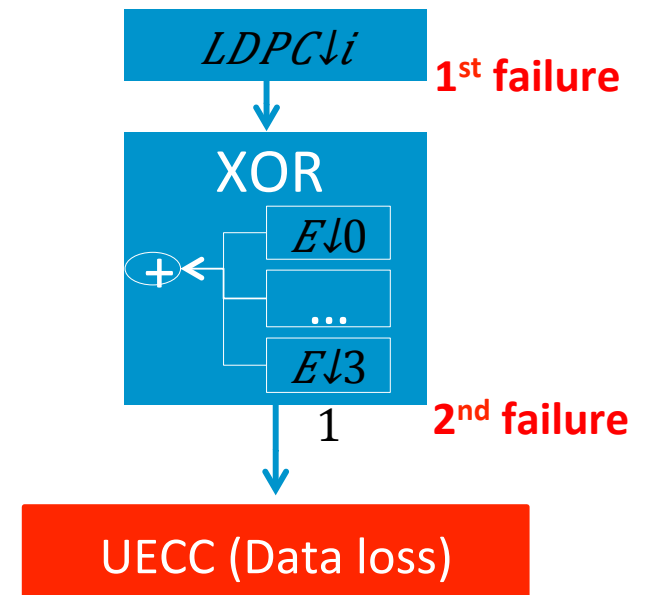


# Case study: 32 Die XOR RAID



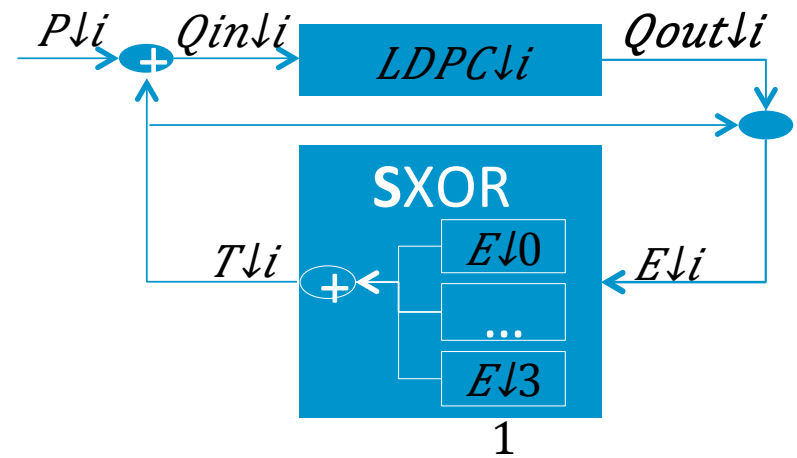
# Current solution

- Decode using soft information
- In case of failure, decode the entire RAID stripe
  - Single error → Recovery
  - More than single error → UECC



# New methodology

- Optimal information exchange between RAID & LDPC
  - Extrinsic “soft” LDPC output → into the RAID
  - Updated “soft” RAID output → back to the LDPC
  - Iterate until convergence or timeout



$$T_i = \varphi^{-1} \left( \sum_j \lambda_j \varphi(E_j) \right),$$

$$\varphi(x) = \{ \text{sign}(x), -\log \tanh(x/2) \}$$

## Previous Work

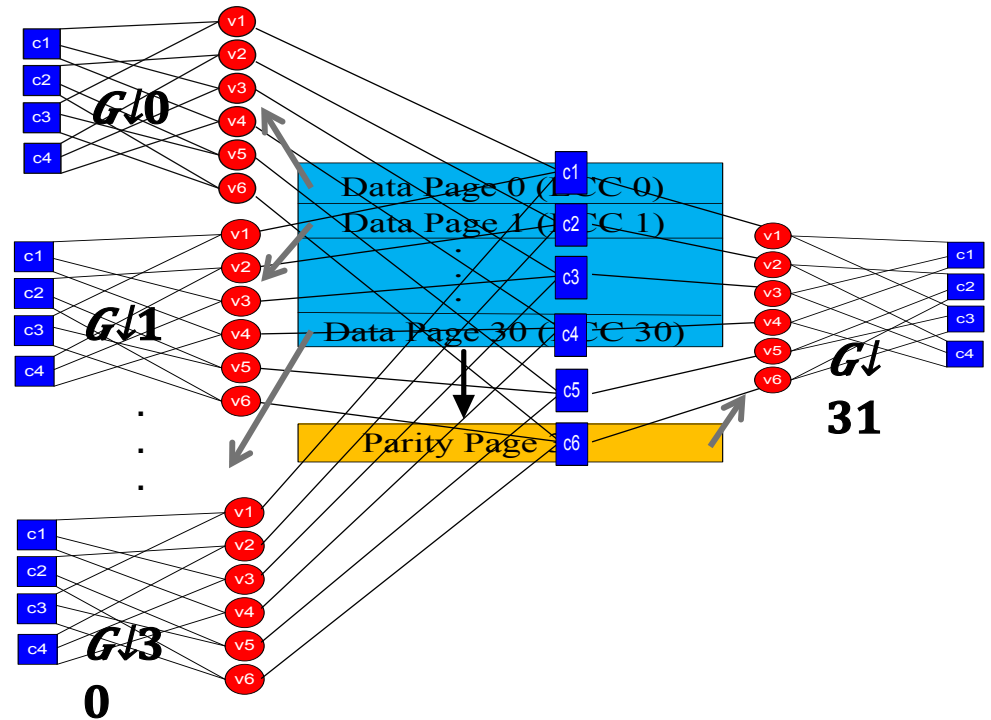
“Error Correction Using Multiple Data Sources” –  
US patent application by Sharon et al (2014, SanDisk)

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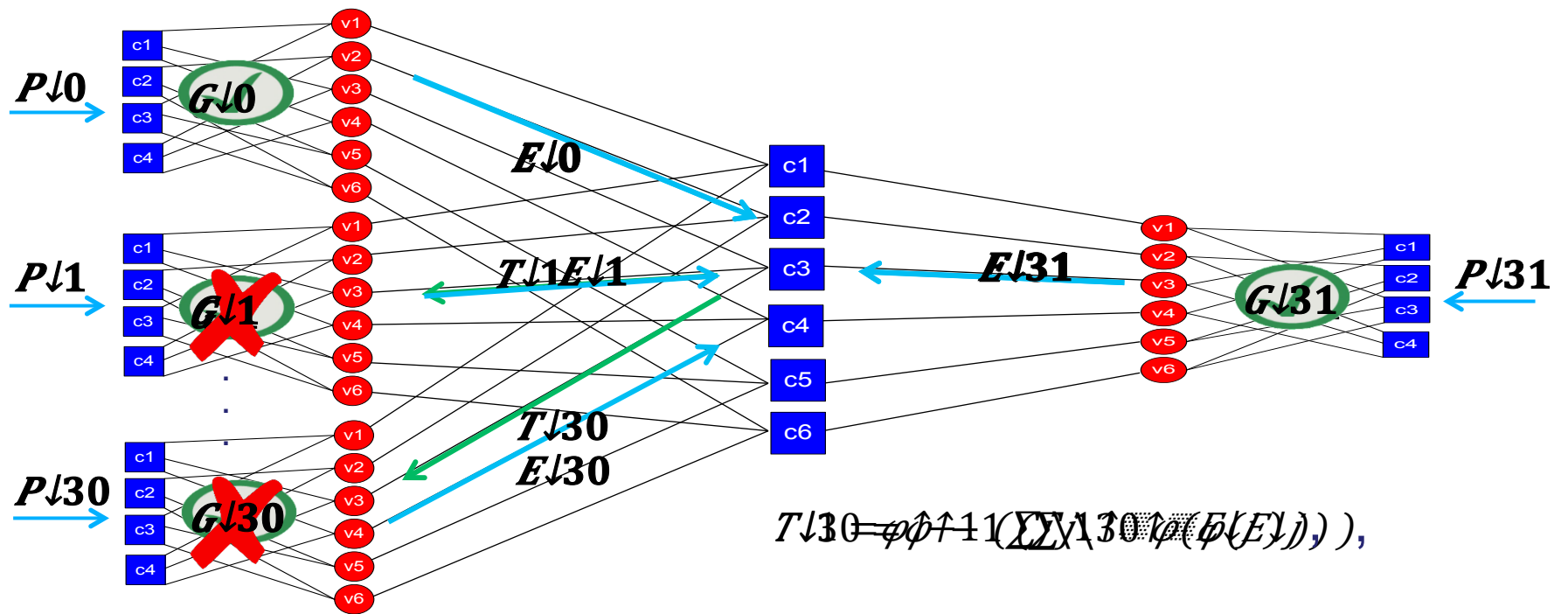
“Soft Decision Decoding of RAID Stripe for Higher Endurance of Flash  
Memory Based Solid State Drives” –  
Ravi Motwani and Chong Ong (2015, Intel)

# Graph Representation

- XOR RAID
- LDPC codewords
- XOR page is a codeword
- Effectively a long code with joint ECC and RAID overprovisioning



# Recovery flow



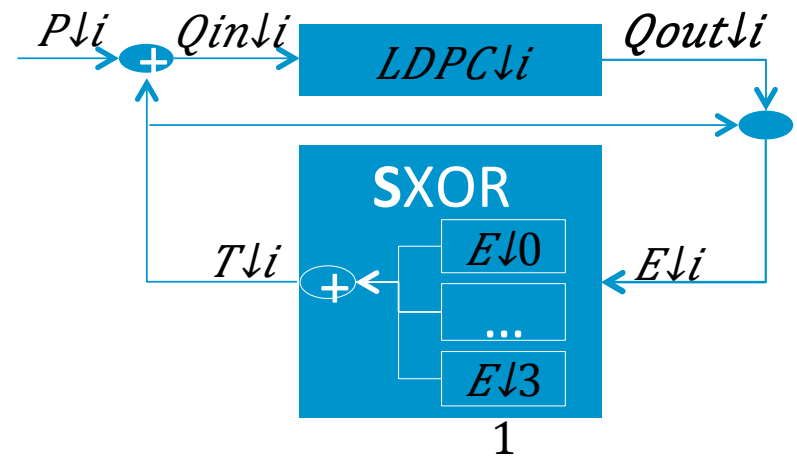
# Pros and Cons

## Pros:

- Enhanced correction capability

## Cons:

- High cost and complexity
  - RAM (Storing  $E_{\downarrow 0}, \dots, E_{\downarrow 31}$ )
  - Soft XOR instead of XOR
  - Latency



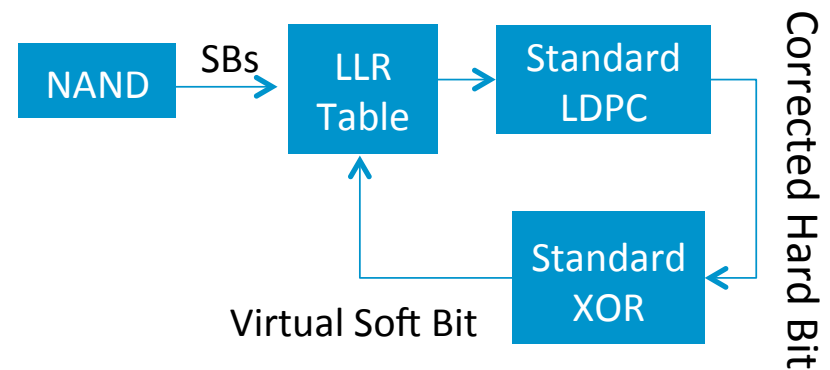
$$T_i = \varphi^{-1} \left( \sum_{j \neq i} \varphi(E_j) \right),$$

$$\varphi(x) = \{ \text{sign}(x), -\log \tanh(x/2) \}$$

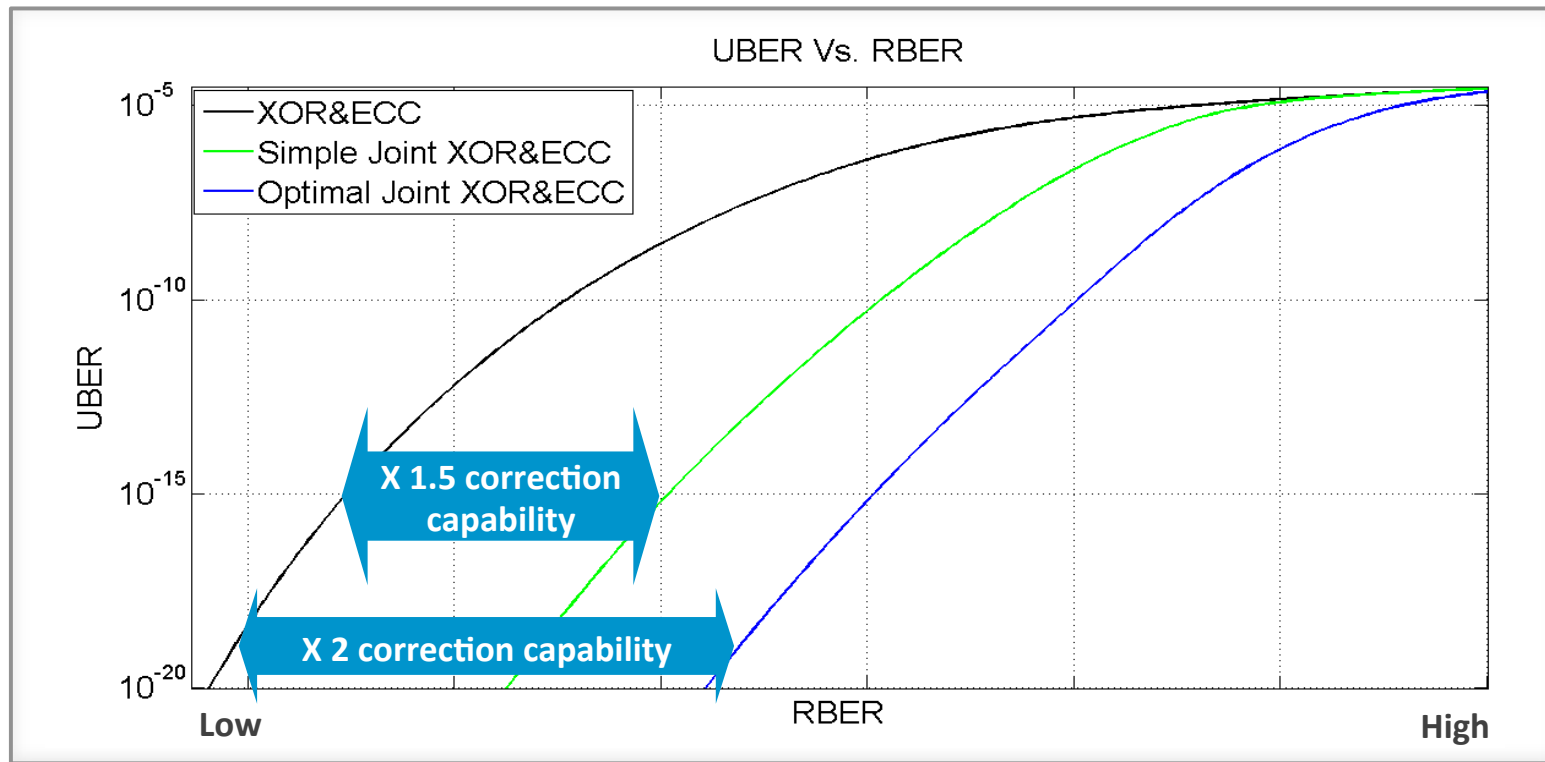


# Simple joint RAID & ECC

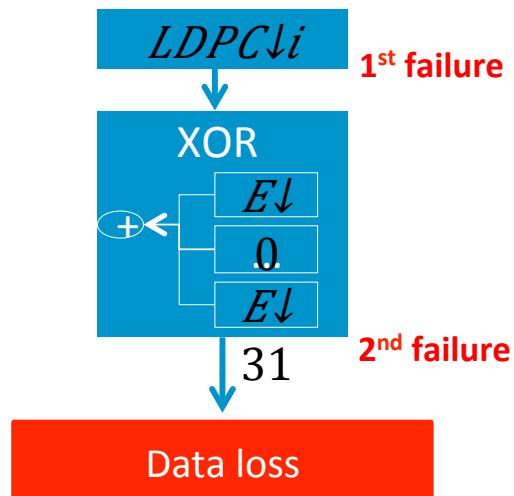
- Simple variant using standard hardware:
  - XOR page as “Virtual” Soft Bit page
  - Dedicated LLR table emulates LLR summation



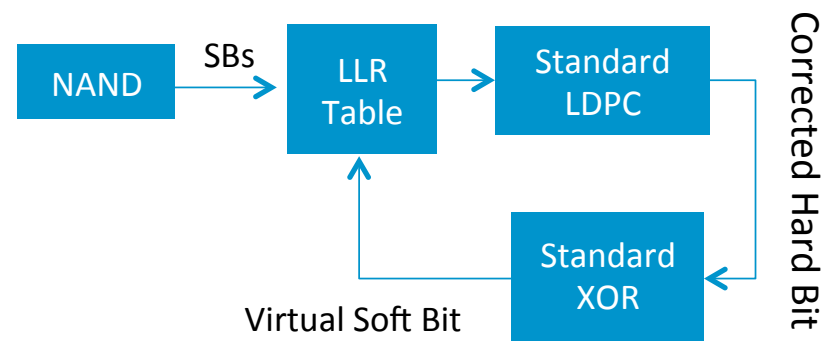
# UBER improvement



# Existing versus New

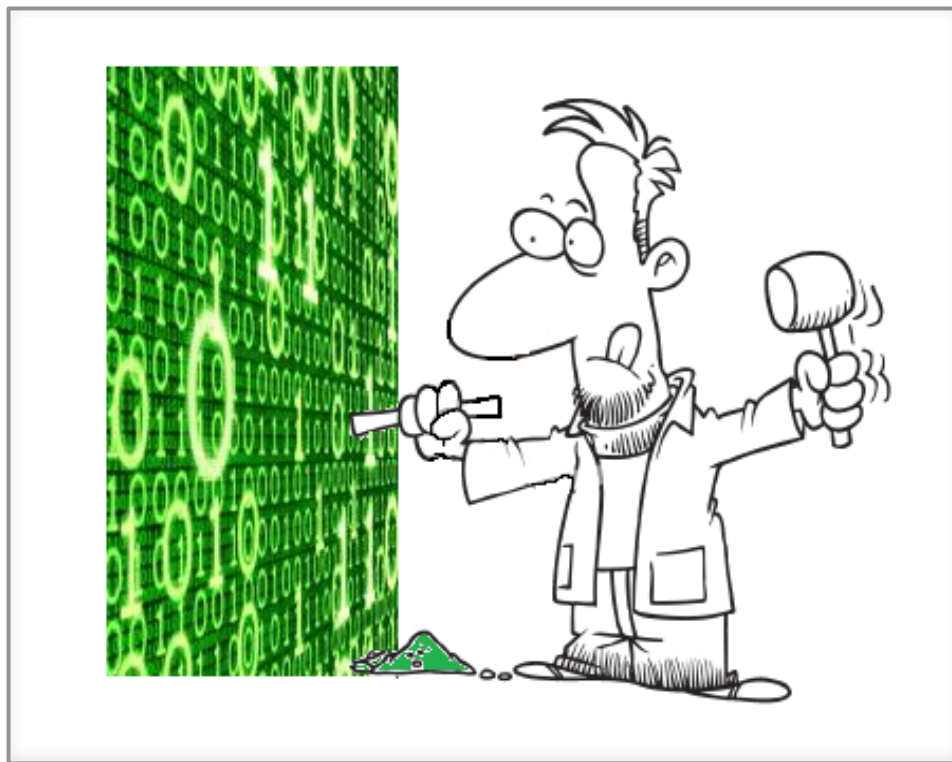


- Independent LDPC & RAID
- Single failure recovery



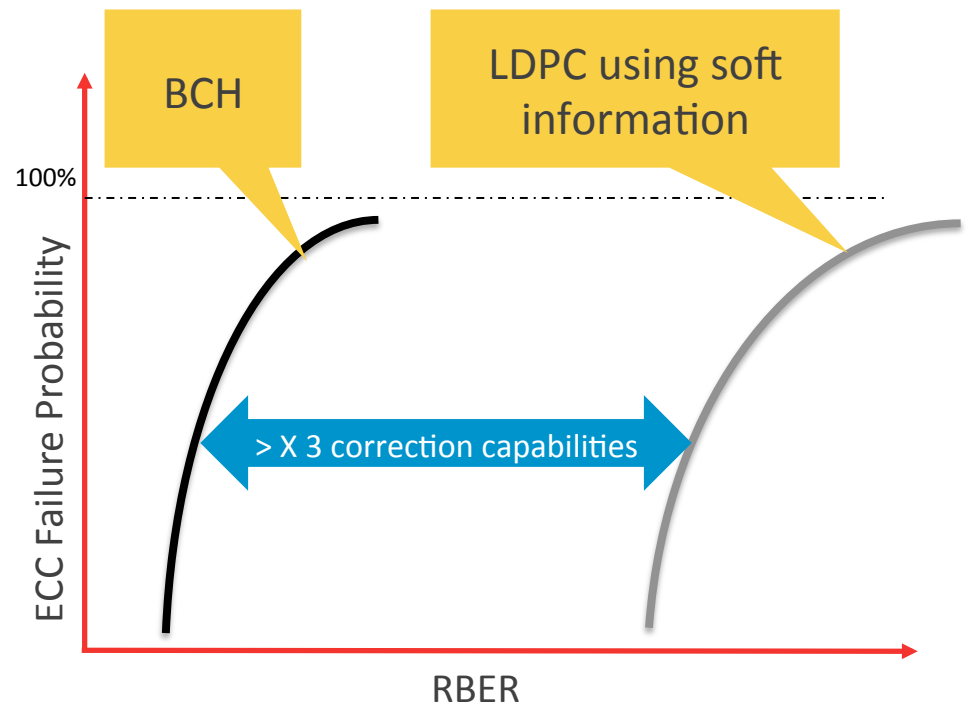
- Joint LDPC & RAID
- Standard HW
- Correcting up to 32 failures
- Substantially reduces UBER

# Joint Hard Decoder and RAID



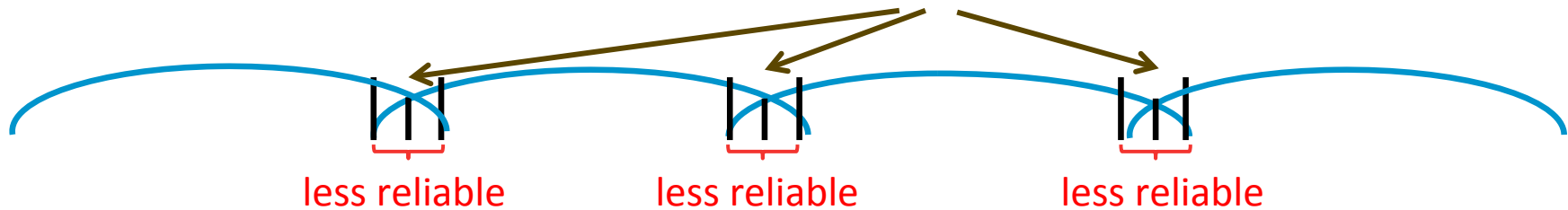
# BCH (Bose, Chaudhuri, Hocquenghem)

- Simple hardware
- Constant latency
- Can not use soft information
- Lower correction capability



# Generating Soft Information

- Soft-Bit read (+/- $\Delta$  around the read thresholds):



- Soft-Bit divides the cells population into two categories:
  - Population of **reliable cells**, exhibiting **low BER**
  - Population of **unreliable cells**, exhibiting **high BER**

# Joint Hard Decoding and RAID

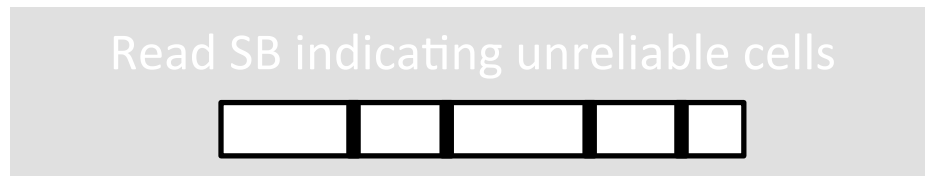
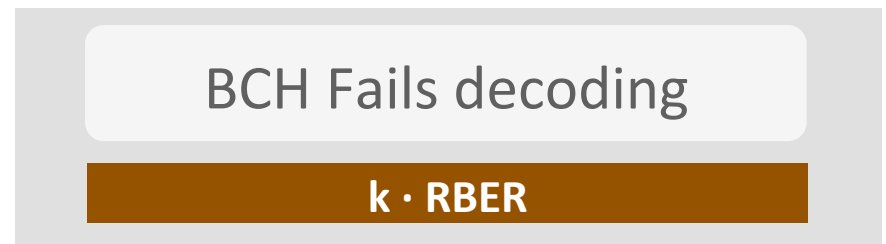
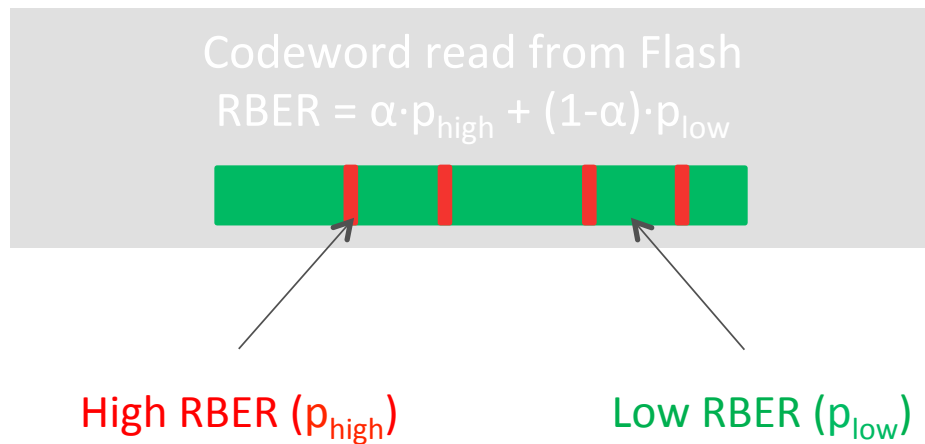
BCH Fails decoding

**RBER**

BCH Fails decoding

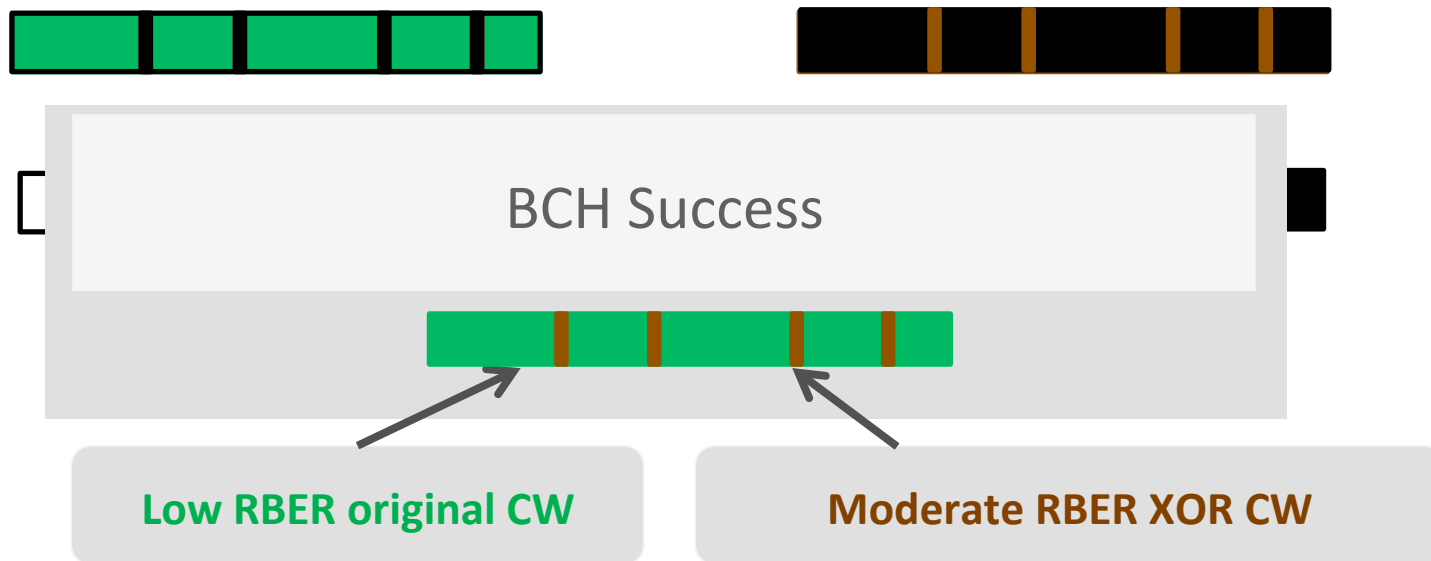
**$k \cdot \text{RBER}$**

# Joint Hard Decoding and RAID

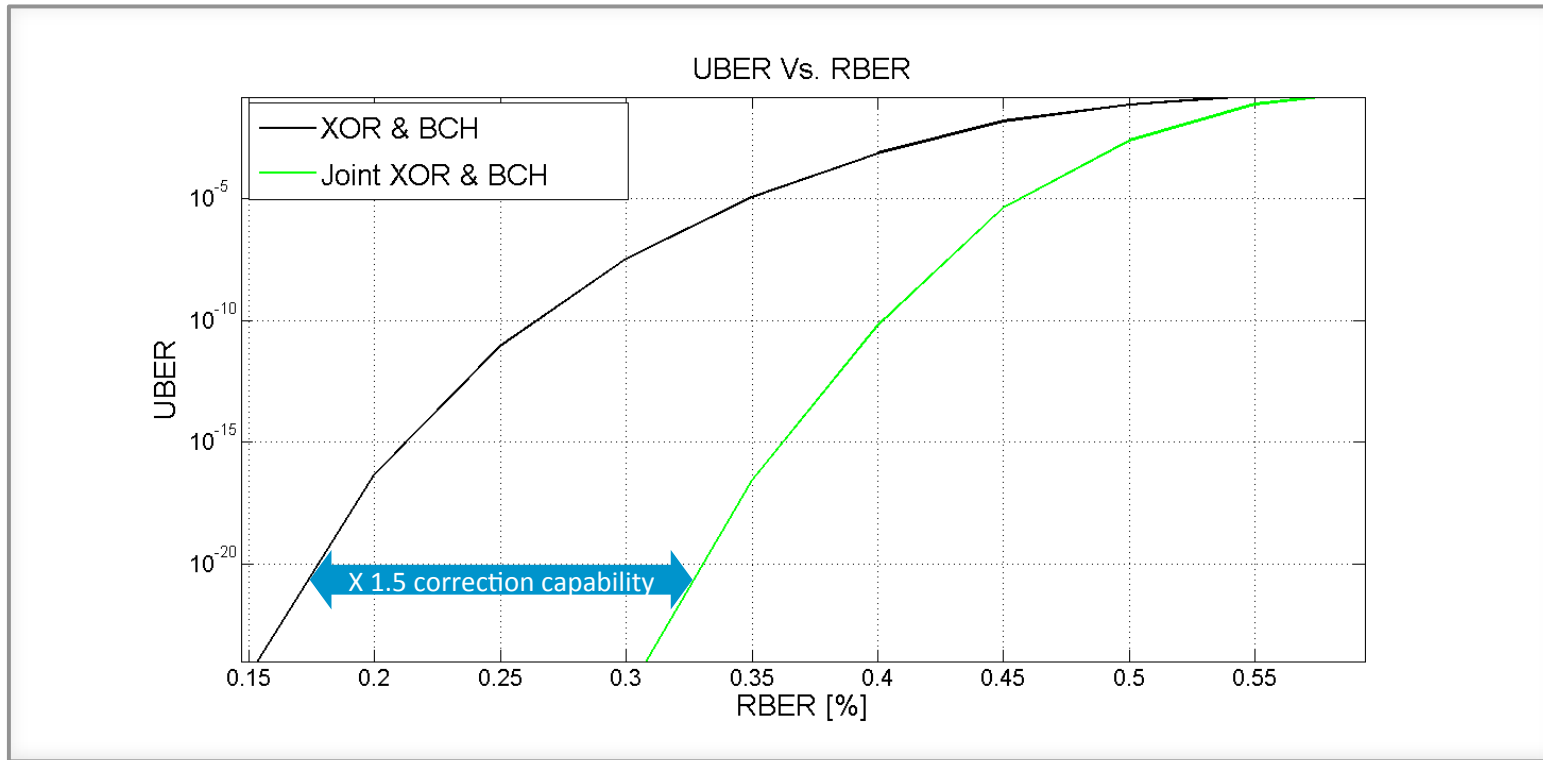




# Joint Hard Decoding and RAID



# UBER improvement

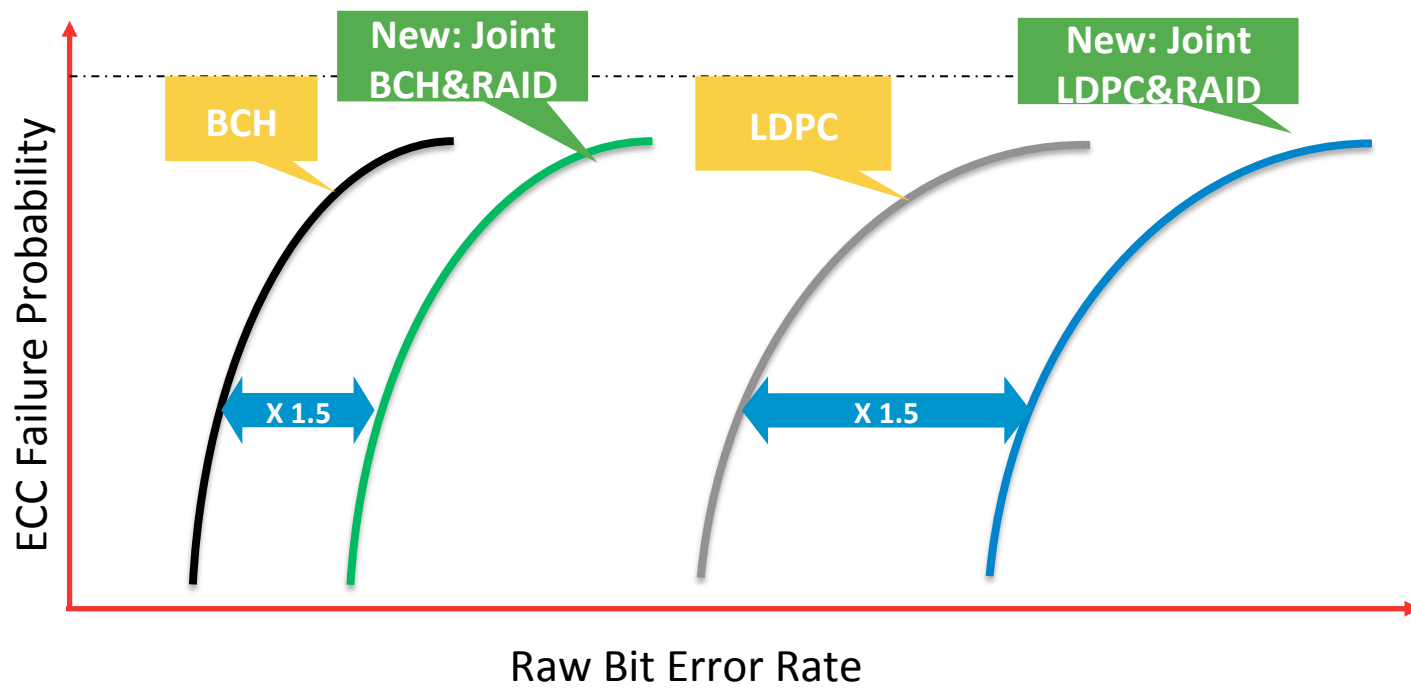


# Summary

- Storage systems require very high reliability
- 3-Dimensional stacking and process scaling increase RBER variability, compromising reliability
- Joint RAID & ECC enhance reliability without adding cost:
  - Soft Decoder – Low complexity joint RAID & LDPC
  - Hard Decoder – Joint RAID & BCH



# Summary





**Thank you!**

**Questions?**

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